

Metromest

International Conference on
Industrial Dimensional Metrology



3 + 4 + 5
MARCH
2020
Bilbao / SPAIN

www.metromest.org

March 3 Marzo

March 4 Marzo

March 5 Marzo

08:30 - 09:00 **Registration + Coffee**

09:00 - 11:30 **TUTORIAL**

Digital and Virtual Metrology
Toni Ventura-Traveset | Datapixel (Spain)

11:30 - 12:15 **Coffee Break + MetroLab INNOVALIA METROLOGY**

12:15 - 12:30 **OPENING**

12:30 - 13:30 **KEYNOTE 1**

A general approach to robot path planning for optical inspections
Boris Bogaerts | University of Antwerp (Belgium)

13:30 - 15:00 **Lunch · Jauregia Restaurant**

15:00 - 16:30 **TRACK 1 · Industrial Metrology Applications**

15:00 - 15:30 3D multisensor coordinate measuring with image processing, microprobes, non-contact 3D sensors and computed tomography
Detlef Ferger | Werth (Germany)

15:30 - 16:00 Probing in integrated CAD/CAM for manufacturing automation
Philip Hewitt | Autodesk (United Kingdom)

16:00 - 16:30 ComMunion Project: 3D metal / Carbon Fiber Reinforced Thermoplastic
Jean-Claude Morel | Topsolid (France)

16:30 - 17:00 **SPECIAL LECTURE - CALIBRATION**

Robot systems accuracy
Gorka Kortaberria | Tekniker (Spain)

20:30 - 23:00 **Conference Banquet · Sociedad Bilbaína**

*Simultaneous translation of all presentations will be made available to all attendees. / Todas las presentaciones tendrán traducción simultánea.
*The organization reserves the right to reschedule, add or cancel presentations. / La organización se reserva el derecho a modificar horarios, añadir o cancelar presentaciones.

08:30 - 09:00 **Registration**

09:00 - 11:30 **MASTER WORKSHOP**

Metrology throughout the machining process
Ainhoa Etxabari | Innovalia Metrology (Spain)

11:30 - 12:15 **Coffee Break**

12:15 - 13:30 **KEYNOTE 2**

The Only thing Constant is Change:
What happens to Quality data when engineering changes happen
Jennifer Herron | Action Engineering (United States)

13:30 - 15:00 **Lunch · Jauregia Restaurant**

15:00 - 16:30 **TRACK 2 · Advanced Metrology**

15:00 - 15:30 Industrial X-ray computed tomography for reverse engineering applications in additive manufacturing
Soraya Plaza & Alejandro Pascual | UPV University (Spain)

15:30 - 16:00 CT on production floor, boosted by Metrology and Collaborative robots
Juan Pablo Morillo | Baker Hughes (Spain)

16:00 - 16:30 Neural-network-based error regression model for close-range photogrammetry
Mohammed Isa | University of Nottingham (United Kingdom)

16:30 - 18:00 **ROUND TABLE + CLOSING**

The Future of Metrology



In the 16th edition of Metromest you will enjoy a third day focused on the Metrology of the future thanks to which we will talk about Digital twins, Artificial Intelligence, Augmented Reality and Management of large amounts of data. You will also enjoy the secrets of a typical Spanish winery while learning about the Future of Metrology.

En la edición 16 de Metromest contarás con un tercer día enfocado a la Metrología del futuro en el que hablaremos de Digital twins, Inteligencia artificial, Realidad aumentada y Gestión de grandes cantidades de datos. Todo ello mientras descubres los secretos de una típica bodega española.

08:15 **Departure from Euskalduna Conference Centre**

08:15 - 10:00 **Trip to the winery + Welcome**

10:00 - 11:00 **Next on Metrology**

10:00 - 10:30 High speed technology for in-line measurements
Laura Francos | Innovalia Metrology (Spain)

10:30 - 11:00 Integration of metrology systems in large pilot lines of metal additive manufacturing
Camilo Prieto | AIMEN (Spain)

11:00 - 11:30 **Coffee Break**

11:30 - 12:30 **Next on Metrology**

11:30 - 12:00 Application of metrology and reverse engineering techniques in Motorsport
Rafael García | MSI (Spain)

12:00 - 12:30 Reality of Big Data and new technologies in the today's Industry
Oscar Lázaro | Innovalia Association (Spain)

12:30 - 13:00 **CLOSING**

13:00 - 14:00 **Winery Tour**

14:15 - 16:00 **Lunch**

16:00 **Journey back to Bilbao**